AMENDMENTS TO THE SPECIFICATION:

Please amend the paragraph beginning at page 15, line 13, as follows:

When the circuit is operating, the load impedance Zl (Ω) of the driver IC 41, created by the side of the circuit containing the measuring instrument 6 as viewed from the line 42 shown in FIG. 3, is changed from the input impedance Zr (Ω) of the receiver IC 43 to $Zr \times (Za + 50)/\{Zr + (Za + 50)\}$ (Ω) by bringing the probe 1 into contact with the conductor patters 9 and 10. In other words, the load impedance Zl (Ω) of the driver IC 41 can be expressed as being formed by a serial connection between the input impedance Zr (Ω) of the receiver IC 43 and the input impedance $Za + 50$ (Ω) of the probe 1, which is the sum of the impedance Za (Ω) in the vicinity of the distal end of the probe 1 and the impedance (50 Ω) of the measuring instrument [[106]] 6.

Please amend the paragraph beginning at page 20, line 10, as follows:

In the electrical characteristics measurement device of the present embodiment, the input impedance $Za + 50$ of the probe 1 can thus be easily changed because a variable resistance element 4 is disposed in the vicinity of the distal end of the probe 1. Also, there is accordingly no longer a need to consider the relationship between the electrical length and the wavelength between the variable resistance element 4 and measurement object 8, and measurement can easily be carried out because the distance H between the measurement object 8 and variable resistance element 4 is made sufficiently less than the measuring wavelength by disposing the variable resistance element 4 in the vicinity of the signal terminal 2 of the probe 1. For example, when the reflection characteristics are measured using the electrical characteristics measurement device and method described above, first, the impedance in the vicinity of the signal terminal 2 is set to 0 by adjusting the resistance value of the variable

resistance element 4, calibration is carried out by using disconnection (infinite), short-circuiting

(0 Ω), and loading (resistance), and the impedance in the vicinity of the signal terminal 2 is set

to a value that is greater than the predictable impedance of the measurement object by varying

the resistance value of the variable resistance element 4 so that measurement can be performed.

For this reason, the reflection characteristics of a measurement object can easily be measured

with good precision by using the electrical <u>characteristics</u> measurement device of the present

embodiment.